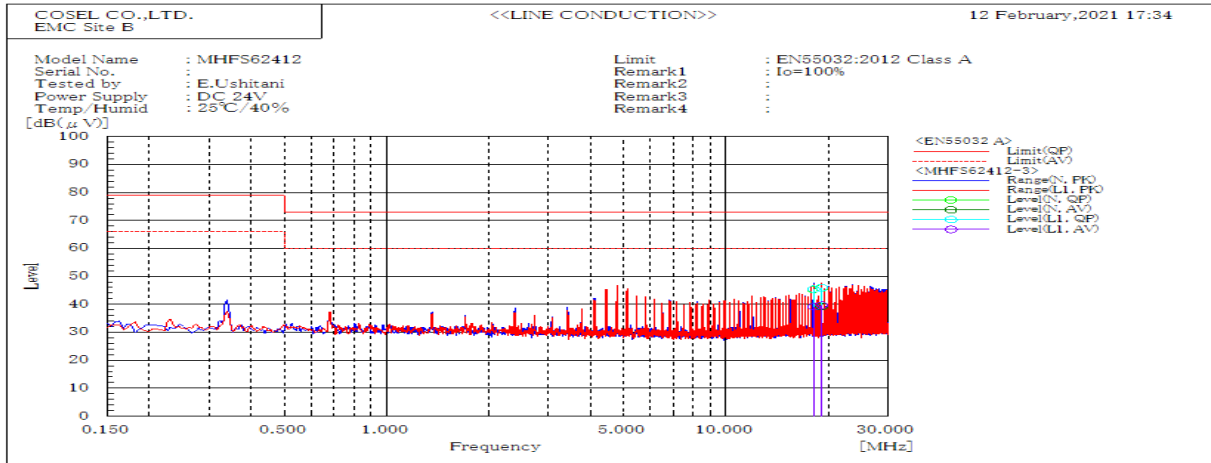
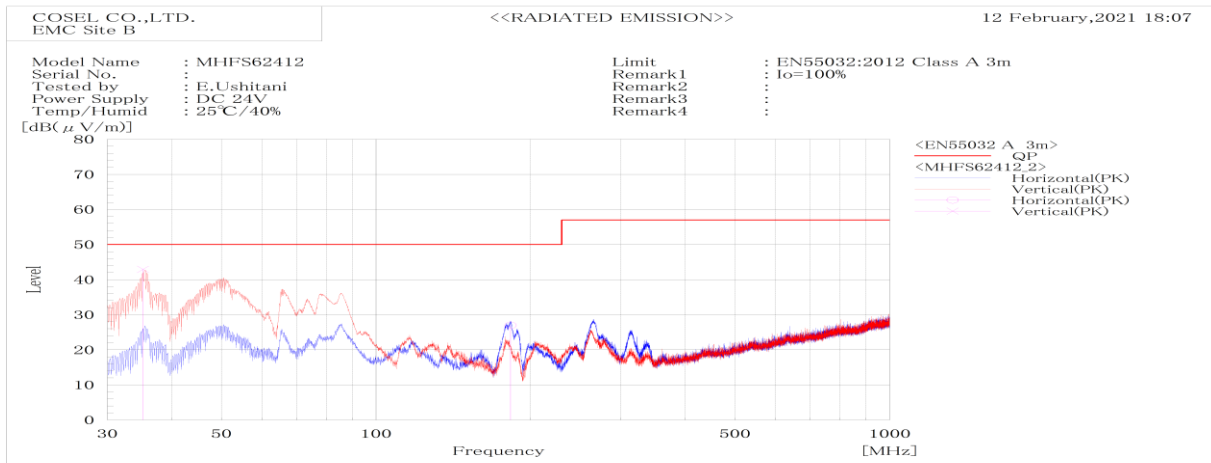


DATA SHEET		Date	05-Nov-21
Model	MHFS62412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



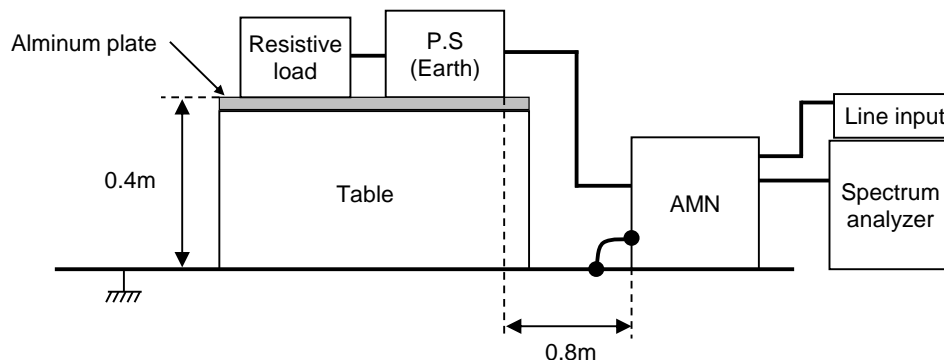
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
19.128	L1	46	39.7	73	60	27	20.3	Pass	
18.107	L1	45.5	39.2	73	60	27.5	20.8	Pass	
19.123	N	45.8	39.2	73	60	27.2	20.8	Pass	
18.105	N	45.3	39.3	73	60	27.7	20.7	Pass	



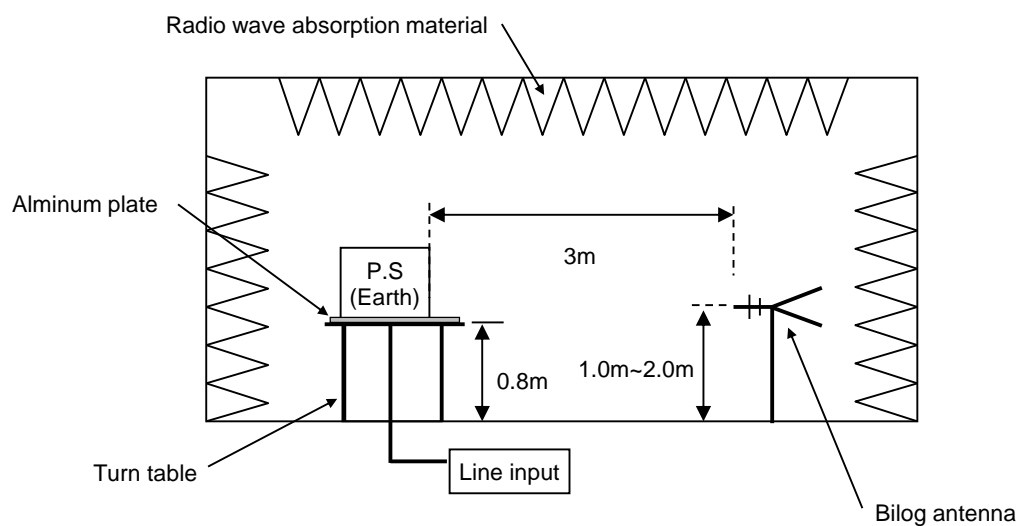
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
182.753	H	Stable	27	50	23	Pass	199.7	346.4	
35.19	V	Stable	42.9	50	7.1	Pass	101.5	282.7	

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission

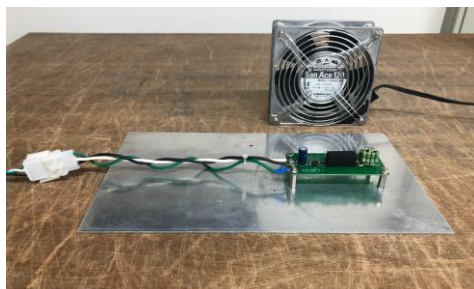


Conditions

Test : EMI
Model Name: MHFS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

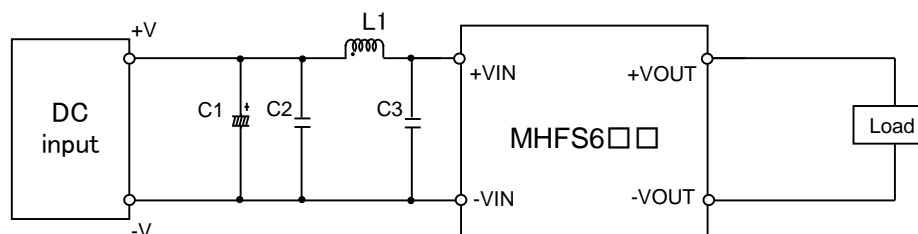


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 μ H Inductor (LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 μ H Inductor (LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 μ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)